Tuesday, May 8, 2018 - Teradyne Users Group

Time				
9:00-9:30 a.m.	**Welcome**			
9:30-10:30 a.m.	**Keynote Address**			
10:30-11:00 a.m.	**Vendor Address (2x 15 minutes)**			
11:00 - 11:30 a.m	**Break**			
Session 1 11:30 a.m.–12:30 p.m.	**RF / Wireless**	**High Power Device and Module Test**	**Extending Test System Capability**	**Memory Test**
11:30 a.m.-12:00 p.m.	**Meeting the Test Challenges of 5G (75)**	**Test Method To Detect Solder Voids in a Power Stack QFN Package (150)**	**UVS256 Temperature/Current Coefficient Measurements (149)**	**A Survey of Magnum's User-Installable Hooks (162)**
12:00 - 12:30 p.m.	**5G, Millimeter Wave Radios, and ATE (140)**	**Achieving Low Cost Test on High Voltage High Current Industrial eFuse Devices. (143)**	**Power-up Slew Rate Control (21)**	**UFS Device Test Solutions Based On Magnum VU System (137)**
12:30-1:30 p.m.	**Lunch**			
Session 2 1:30–3:00 p.m.	**RF / Wireless**	**High Power Device and Module Test**	**Extending Test System Capability**	**Ensuring Product Quality**
1:30-2:00 p.m.	**mmWave(5G) Test Strategy (39)**	**Power Simulation for ETS88TH Load Board Design: Capacitance vs. Inductance (125)**	**Introduction of Extreme Pure Clock Solution based on LMK04828 (106)**	**Final Test Quality Improvement using Moving Dynamic Part Average Test Limits (64)**
2:00-2:30 p.m.	**Challenges of Over-The-Air Testing at 60 GHz mmWave (8)**	**UHV DIB Design Challenges and Solutions (130)**	**Designing an External Instrument for Smart Phone Quick Charge Applications (128)**	**Automated Spike Checker (1)**
2:30-3:00 p.m.	**Resolving Dual Tone Test Dilemmas Using an IQ Modulation Methodology (102)**	**Hardware Interface Design Consideration for IPM Devices on ETS-88TH (111)**	**Achieving Force Accuracies Better Than the Published Spec. on VI's (153)**	**Advanced Datalog Tool for Live Data Analysis (12)**
3:00-3:30 p.m.	**Expectation and Actual Result of Concurrent Test for SIP Device (117)**	**Mother Board + AC/DC Socket Board Solution for IGBT Testing on ETS-88TH Platform (123)**	**A Generic DIB Diagnostics Solution (89)**	
3:30-4:00 p.m.	**Break**			
Session 3 4:00–5:30 p.m.	**RF / Wireless**	**High Power Device and Module Test**	**Extending Test System Capability**	**Manufacturing Test Flow**
4:00 - 4:30 p.m.	**Adaptive RF-DIB for ATE and Bench Reducing NRE-cost and Cycle Time (97)**	**ESU Interface Solution on ETS88-TH Platform: Stiffener Interface and Soft-Cable Interface (122)**	**Waveform Analyzer Tool (76)**	**Panel Level Packaging (147)**
4:30 - 5:00 p.m.	**J750-LitePoint TTR (13)**	**Balanced Test Technique for Elimination of Setup Induced Errors in Sensitive High Current Output Measurement Using Eagle 364 Tester (86)**	**IG-Data's Potential For Dealing With IG-XL Program (94)**	**What's The Best Probe Technology For My Device? (74)**
5:00 - 5:30 p.m.	**Phase Measurement on Different RF Channels (151)**	**If You Can't Measure It, You Can't Improve It -- An OEE System for EagleVision MST (144)**	**J750 Test Time Analysis With Only A Few Steps - The New Profiler (135)**	**Test Cost Optimization on Test Insertion Strategies (20)**
5:45-8:30 p.m.	**Teradyne Party**			

VENDOR FAIR -

10:30 a.m. - 5:00 p.m.

Wednesday, May 9, 2018 - Teradyne Users Group

9:00-10:00 a.m.	**Semiconductor Business Meeting & Engineering Update**				
10:00-10:30 a.m.	**Break**				**VENDOR FAIR - 10:00 a.m. - 5:00 p.m.**
Session 4 10:30 a.m.–12:00 p.m.	**Automotive**	**High Speed Serial**	**DIB Design**	**Testing Fundamentals**	
10:30–11:00 a.m.	**Importance of Alarms in Automotive Test (26)**	**MIPI M-PHY Simulation with IBIS-AMI Model for UFS Signal Integrity Analysis (121)**	**Choosing the Right PCB Stackup Technology For Your Teradyne UltraFLEX Test Boards (99)**	**Leveraging the Power of the J750 DSIO for a Variety of Applications and Test Time Improvements (36)**	
11:00 -11:30 a.m.	**ETS-800 Safe Connection Analyzer (71)**	**Octal sites 1040MBps Eye Diagram Testing On UP1600 (14)**	**Electrical-Thermal Co-Simulation for Current Capacity in Fine Pitch DIB Design (116)**	**Virtual Parallel Site: How to Extend the J750 HD Capability To Use the DSIO In Parallel Mode For High Site Count Applications (141)**	
11:30 - 12:00 p.m.	**ETS800 SPU2112 Sharing Techniques for Applications Requiring >10A (4)**	**CDR and TTR Work-arounds on UltraPin1600 (16)**	**Novel DIB Layout Solution to Minimize Load Capacitance in pico-Amps Measurement (83)**	**Capacitor Measurement on J750HD for HDDPS, HDAPMU, HDCTO and HSD800 (65)**	
12:00-1:00 p.m.	**Lunch**				
Session 5 1:00–3:00 p.m.	**Automotive**	**High Speed Serial**	**LitePoint**	**Testing Fundamentals**	
1:00-1:30 p.m.	**Accelerating Automotive Testing With UPD-64 (72)**	**Extending Walking Strobe and GigaDig Performance By Correcting DIB and Instrument Loss (161)**	**The Internet Of Things (IOT) Testing Matters (105)**	**Threshold Test Methods Summary on ETS800 (62)**	
1:30-2:00 p.m.	**Low Leakage Measurements: With or Without APU-12? (11)**	**US10G Solutions - Jitter Measure/Functional Receive Above 10.7Gbps and Fast CMEM Unpacking (40)**	**MIPI RFFE Testing in Wireless Mobile Devices (108)**	**Reduction of Application-related Failure at Teradyne FLEX Tester Platform (133)**	
2:00-2:30 p.m.	**Handy Temperature Monitoring For Eagle Test Systems Measurement Resources to Guarantee High Precision Measurement results to Spec (6)**	**Addressing 28Gbps SerDes Reference Clock Requirements By Low Jitter Clock Module (9)**	**GaN RF Device Trend and GaN Power Amplifier Test Challenges (110)**	**Digital Signal Processing vs. Background Processing (156)**	
2:30-3:00 p.m.	**The Study and Miscorrelation Correction of Signal Reflection on Nanosecond-scale Switching Characteristics Measurements (98)**	**56Gbps PAM4 and RF Together On UltraFLEX (145)**	**5G mmWave RF Testing (107)**	**Integration of Universal Robot into Performance Verification Test Process (87)**	
3:00-3:30 p.m.	**Break**				
Session 3 3:30–5:00 p.m.	**Eagle Tutorial**	**High Speed Digital**	**Testing Fundamentals**	**Testing Fundamentals**	

3:30-4:00 p.m.	**Visual Studio 2015 Conversion Strategy for ETS Test Applications (146)**	**The Optimal Solution Of Accessing Device Using Register Mirror Method Through PA Module (95)**	**An IGXL Add-Ins for Limit-Sets Function (148)**	**Performance and Memory Advantages Of Using 64-bit IG-XL (136)**	
4:00-4:30 p.m.		**How to Deal with DUT Nondeterministic Behavior Using nWire PA (96)**	**An Analysis of Big Difference of SHMOO Between Different ATE (129)**	**How to Setup SSL Local Server License Without Unexpected Happening (119)**	
4:30-5:00 p.m.			**The Multi-Site Testing Solutions for Display PMIC Device (28)**	**Flexibility and Efficiency of a Centralized Licensing Service (127)**	